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Substitute for form 1449/PTO				Complete if Known		
				Application Number	10/554,059-Conf. #7920	
11	NFORMATIO	N DIS	CLOSURE	Filing Date	September 1, 2006	
S	TATEMENT	BY AF	PPLICANT	First Named Inventor	Akira Otomo	
				Art Unit	1792	
	(Use as many sheets as necessary)			Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attomey Docket Number	32011-224744	

			U.S. PA	TENT DOCUMENTS		
Examiner Cite Initials* No.1		Document Number  Number-Kind Code <sup>2</sup> ( <i>if known</i> )  Publication Date MM-DD-YYYY		Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
	AA*	US-6,537,800-B1	03-25-2003	Karube et al.	Corresponding to WO99/46588	

		FOREI	GN PATENT	DOCUMENTS		
Examiner Initials*	Cite No.1	Foreign Patent Document  Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (If known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	
	BD	WO-99/46588	09-16-1999	Shimizu, Hatsushi et al.	Corresponds to US 6,537,800	
	BE	JP-2001-277200	10-09-2001	Toshiba Corp.		

Examiner	Date	
1	24.0	
Signature	Considered	
	Contractor	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance end not considered. Include copy of this form with next communication to applicant. \* CITE NO.: Those application(s) which are marked with an single esterisk (\*) next to the Cite No. ere not supplied (under 37 CFR 1.98(e)(Z)(iii)) because that epplication was filed after June 30, 2003 or is available in the IFW. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents et <a href="https://www.uspto.gov">www.uspto.gov</a> or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁴ Applicant is to place a check mark here if English language Translation is attached.

Examiner Initials	Cite No. <sup>1</sup>	Include name of the author ( in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journ al, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
	cu	A. Majumdar, et al., "Nanometer-scale lithography using the atomic force microscope" Appl. Phys. Lett, November 9, 1992, Vol. 61, No. 19, pp. 2293-2295	
	cv	Japanese Office Action in Japan Patent Application No.: 2005-505876, dated June 16, 2009, with English language translation	

Examiner Signature /Robert S. Walters Jr./	Date Considered	12/02/2009
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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